

List of publications:**Impact of real mirror profiles inside a split-and-delay unit on the spatial intensity profile in pump/probe experiments at the European XFEL**

V. Kärcher, S. Roling, L. Samoylova, A. Buzmakov, U. Zastra, K. Appel, M. Yurkov, E. Schneidmiller, F. Siewert and H. Zacharias

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The TRIXS end-station for femtosecond time-resolved resonant inelastic X-ray scattering experiments at the soft X-ray free-electron laser FLASH

S. Dziarzhytski, M. Biednov, B. Dicke, A. Wang, P. S. Miedema, R. Y. Engel, J. O. Schunck, H. Redlin, H. Weigelt, F. Siewert, Ch. Behrens, M. Sinha, A. Schulte, B. Grimm-Lebsanft, S. G. Chiuzbăian, W. Wurth, M. Beye, M. Rübhausen and G. Brenner

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A hard x-ray split-and-delay unit for the HED Instrument at the European XFEL

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Metrology, Mirrors and Gratings – Advances and Challenges in Synchrotron Optics

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Investigations on the spatial resolution of autocollimator-based slope measuring profilers

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